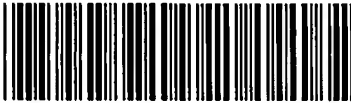


Search Notes

Application/Control No.

10/761,326

Examiner

Tan V. Mai

Applicant(s)/Patent under
Reexamination

FUJITA ET AL.

Art Unit

2193

SEARCHED

Class	Subclass	Date	Examiner
708	251, 254	8/1/2007	MAI

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	8/1/2007	MAI